NSTAR-200近红外光谱透反射性能测量系统
NSTAR-200 near-infrared spectral transmittance and reflectance measurement system

- NSTAR-200近红外光谱透反射测量系统集反射和透射测量功能于一体，用于测量材料的光谱反射率/光谱透过率，测量波段范围覆盖780-1600nm。系统应用远方公司多项专利技术，可快速精确测量近红外宽波段范围内光谱透反射率，系统测量灵敏度高，稳定性、复现性好，杂散光小，可满足较低透反射率的深色样品测量，主要用于各类材料研发实验室。

The NSTAR-200 near-infrared spectral reflectance measurement system integrates reflection and transmission measurement functions, and is used to measure the spectral reflectance/spectral transmittance of materials. The measurement band range covers 780-1600nm. The system applies a number of patented technologies of the remote company, which can quickly and accurately measure the spectral transmittance and reflectivity in the near infrared wide band range. The system has high measurement sensitivity, good stability and reproducibility, and small stray light, which can meet the requirements for measuring dark samples with low transmittance and reflectivity. It is mainly used in various material research and development laboratories.



特点与优势 Characteristics and advantage

- 兼容反射和透射测量：反射测量d/8，SCI和SCE可选；透射测量为d/0几何；
  Compatible with reflection and transmission measurement: reflection measurement d/8, SCI and SCE optional; The transmission measurement is d/0 geometry;
- 附NPL溯源标准色板，溯源性好；
  NPL traceable standard color plate is attached, with good traceability;
- 稳定性好，测量精度高，满足较低透反射率的深色样品测量。
  It has good stability and high measurement accuracy, meeting the requirements for measuring dark samples with low transmittance and reflectivity.

技术参数 Specifications

型号	NSTAR-2000
测量几何	兼容透反射测量
波长范围	780nm ~ 1600nm
波长准确度	±0.5nm
反射率范围	0-100%
测量重复性	0.2%
测量孔径	反射测量：Φ28mm　透射测量：Φ20mm
接口	USB